



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANT : Paul Hansma et al.

SERIAL NO.: 08/709,349

FILED : 9/6/96

FOR : Atomic Force Microscope
for Generating a Small Incident Beam

DOCKET NO.: 1279-225XX

) Examiner Unknown

) Art Unit 2516

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3-18-98
RECEIVED

MAR 17 1998

GROUP 2500

AMENDMENT

March 5, 1998
865 South Figueroa Street #2800
Los Angeles, California 90017
(213) 892-9200

Asst. Commissioner for Patents
Washington, D. C. 20231

Sir:

In response to the Office Action of November 10, 1997, please cancel
claim 2, amend claims 1, 3, and 10, and add claim 24 as follows:

IN THE CLAIMS:

1.(Amended) In an atomic force microscope including
at least one cantilever mounted therein and an optical detector, the
improvement, for generating a small incident beam spot, comprising:
an optical system including a light source and means for
producing [a focused] an incident beam, and at least one lens for focusing said
incident beam; and